



P.O. BOX 265
OGDENSBURG, NY
U.S.A. 13669-0265

TEL: 888-670-8729 (USA & Canada) or +1-613-686-6675 (Intl)
FAX: 800-561-1970 (USA & Canada) or +1-613-686-6679 (Intl)

BOX 5120, LCD MERIVALE
OTTAWA, ONTARIO
CANADA K2C 3H4

info@avtechpulse.com - http://www.avtechpulse.com/

PERFORMANCE CHECKSHEET

Model: AVR-EB2A-B
Type: Semiconductor Device Tester
S.N.: 12516
Date: October 20, 2010

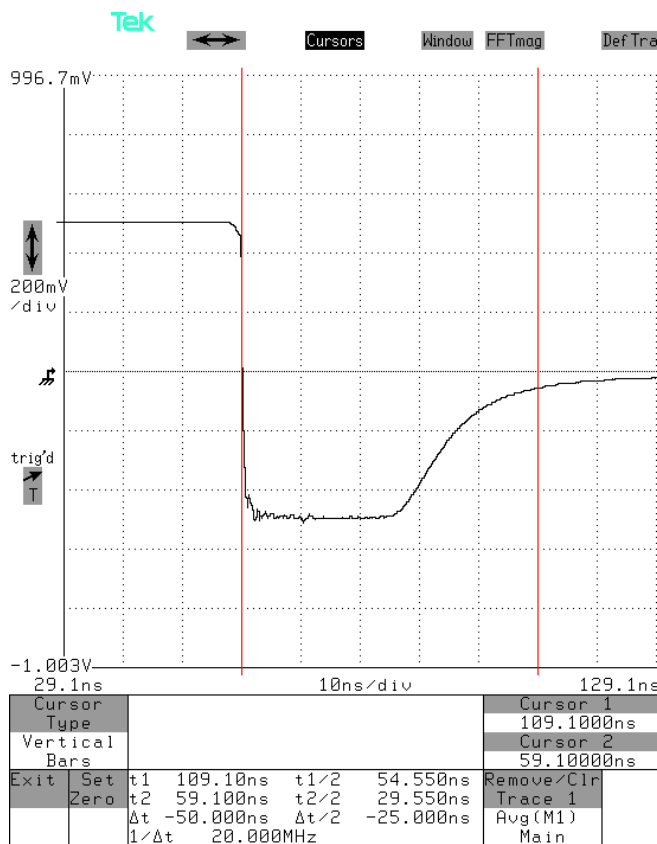
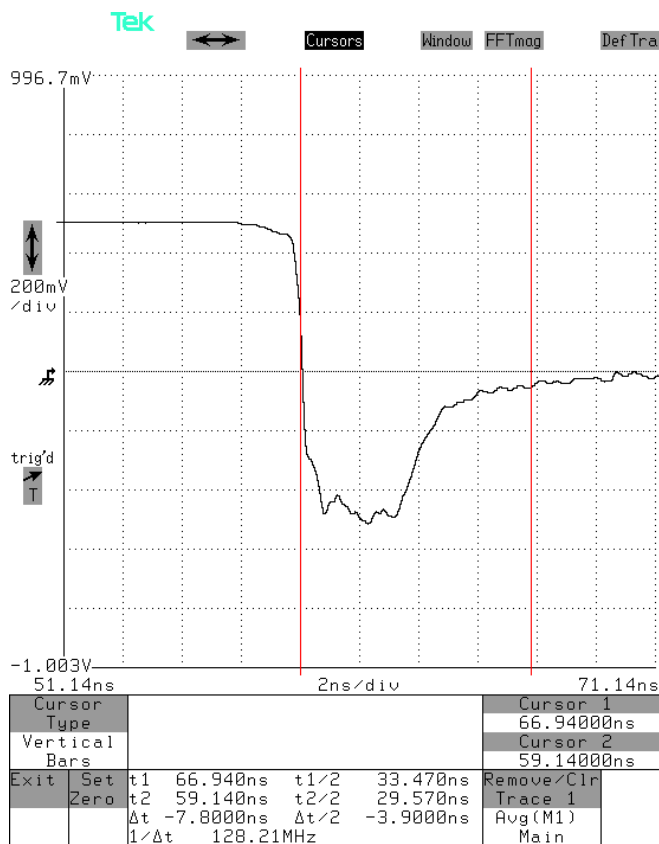
Output Amplitude: to +100 mA, -100 mA
Pulse Width (FWHM): 200 ns
Switching Time,
+ to -, 10%-90%: ≤ 300 ps (at mainframe)
PRF: 1 - 10 kHz
Jitter, Stability: OK
Prime Power: 100-240V AC, 50-60 Hz.

Basic specifications: →

Test Waveforms

With a 1N4148 installed in the AVX-CA-AR1 test jig, 40 mA/div, 2 ns/div:

With a 1N5811US installed in the AVX-CA-AR1 test jig, 40 mA/div, 10 ns/div:



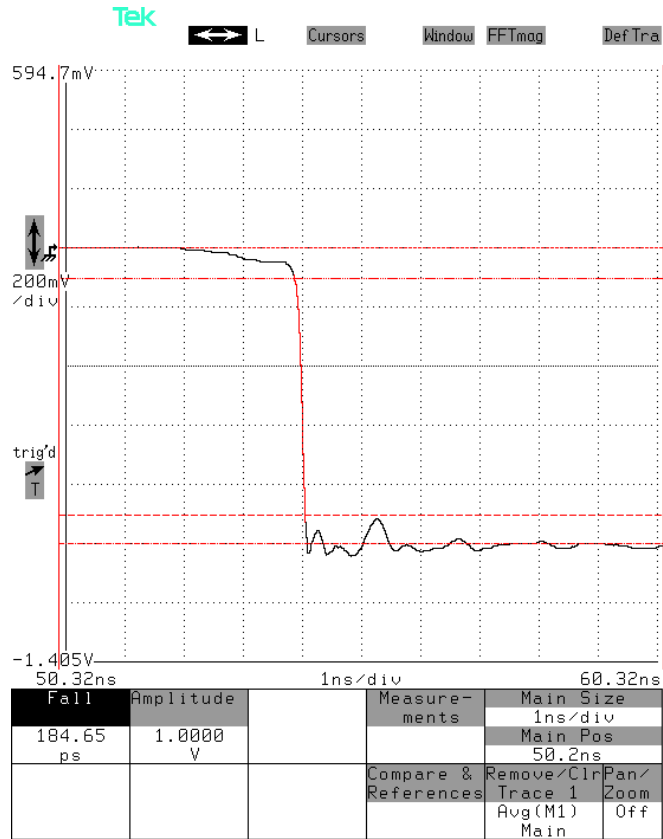
$I_F = +100 \text{ mA}$, $I_R = -100 \text{ mA}$

$I_F = +100 \text{ mA}$, $I_R = -100 \text{ mA}$

Measured $t_{RR} = 7.8 \text{ ns}$.

Measured $t_{RR} = 50 \text{ ns}$.

Pulse output directly from mainframe, with the test jig bypassed (2 V/div, 2 ns/div):



Shows a 10%-90% transition time of 185 ps.

For more sample waveforms, please see the "Typical Results" section of the manual.